

# International IR Rectifier

PD - 94630

## SMPS MOSFET IRFPS38N60L

HEXFET® Power MOSFET

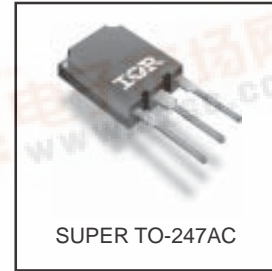
### Applications

- Zero Voltage Switching SMPS
- Telecom and Server Power Supplies
- Uninterruptible Power Supplies
- Motor Control applications

V <sub>DSS</sub>	R <sub>DS(on)</sub> typ.	T <sub>rr</sub> typ.	I <sub>D</sub>
600V	120mΩ	170ns	38A

### Features and Benefits

- SuperFast body diode eliminates the need for external diodes in ZVS applications.
- Lower Gate charge results in simpler drive requirements.
- Enhanced dv/dt capabilities offer improved ruggedness.
- Higher Gate voltage threshold offers improved noise immunity.



### Absolute Maximum Ratings

Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	38	A	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	24		
I <sub>DM</sub>	150		
P <sub>D</sub> @ T <sub>C</sub> = 25°C	540	W	
	Linear Derating Factor	4.3	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	±30	V
dv/dt	Peak Diode Recovery dv/dt	13	V/ns
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to + 150	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	1.1(10)	

### Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	38	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	150		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.5	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 38A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	170	250	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 38A
		—	420	630		T <sub>J</sub> = 125°C, di/dt = 100A/μs ④
Q <sub>rr</sub>	Reverse Recovery Charge	—	830	1240	nC	T <sub>J</sub> = 25°C, I <sub>S</sub> = 38A, V <sub>GS</sub> = 0V ④
		—	2600	3900		T <sub>J</sub> = 125°C, di/dt = 100A/μs ④
I <sub>RRM</sub>	Reverse Recovery Current	—	9.1	14	A	T <sub>J</sub> = 25°C
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				



# IRFPS38N60L

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## Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	600	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.41	—	V/°C	Reference to $25^\circ\text{C}, I_D = 1mA$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	120	150	m $\Omega$	$V_{GS} = 10V, I_D = 23A$ ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	50	$\mu A$	$V_{DS} = 600V, V_{GS} = 0V$
		—	—	2.0	mA	$V_{DS} = 480V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 30V$
	Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{GS} = -30V$
$R_G$	Internal Gate Resistance	—	1.2	—	$\Omega$	$f = 1MHz, \text{open drain}$

## Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{fs}$	Forward Transconductance	20	—	—	S	$V_{DS} = 50V, I_D = 23A$
$Q_g$	Total Gate Charge	—	—	320	nC	$I_D = 38A$ $V_{DS} = 480V$ $V_{GS} = 10V, \text{See Fig. 7 \& 15 } \textcircled{4}$
$Q_{gs}$	Gate-to-Source Charge	—	—	85		
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	160		
$t_{d(on)}$	Turn-On Delay Time	—	44	—	ns	$V_{DD} = 300V$ $I_D = 38A$ $R_G = 4.3\Omega$ $V_{GS} = 10V, \text{See Fig. 11a \& 11b } \textcircled{4}$
$t_r$	Rise Time	—	130	—		
$t_{d(off)}$	Turn-Off Delay Time	—	92	—		
$t_f$	Fall Time	—	69	—		
$C_{iss}$	Input Capacitance	—	7990	—	pF	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1.0MHz, \text{See Fig. 5}$ $V_{GS} = 0V, V_{DS} = 0V \text{ to } 480V \textcircled{5}$
$C_{oss}$	Output Capacitance	—	740	—		
$C_{riss}$	Reverse Transfer Capacitance	—	72	—		
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	350	—		
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)	—	260	—		

## Avalanche Characteristics

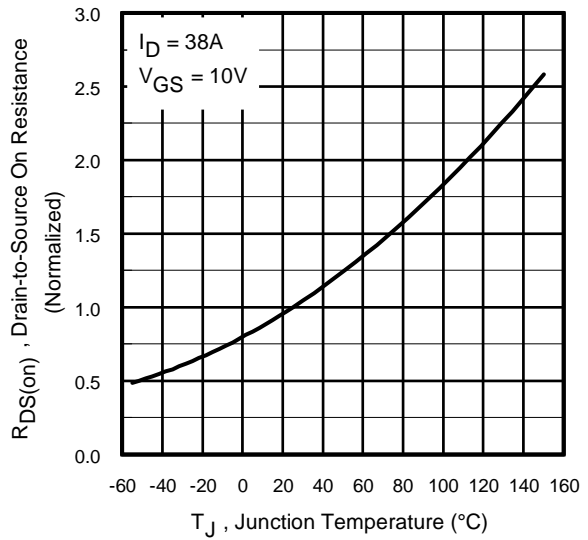
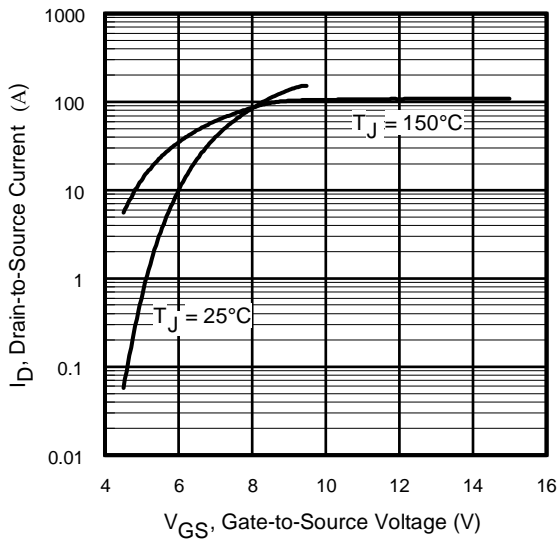
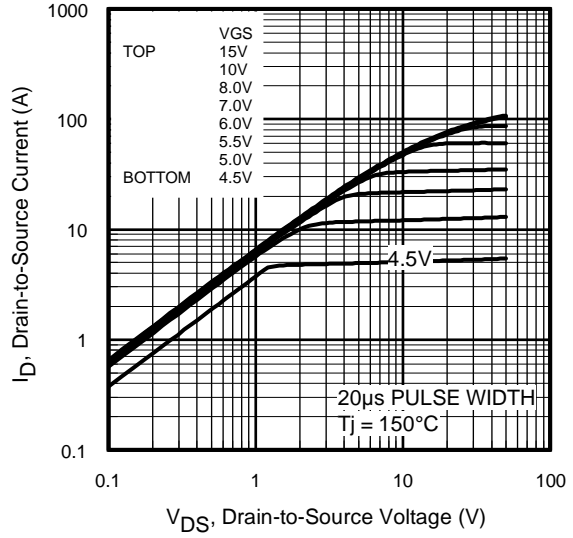
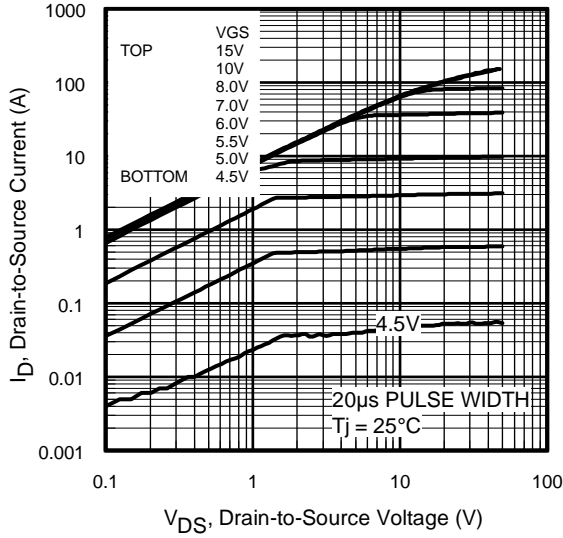
Symbol	Parameter	Typ.	Max.	Units
$E_{AS}$	Single Pulse Avalanche Energy ②	—	680	mJ
$I_{AR}$	Avalanche Current ①	—	38	A
$E_{AR}$	Repetitive Avalanche Energy ①	—	54	mJ

## Thermal Resistance

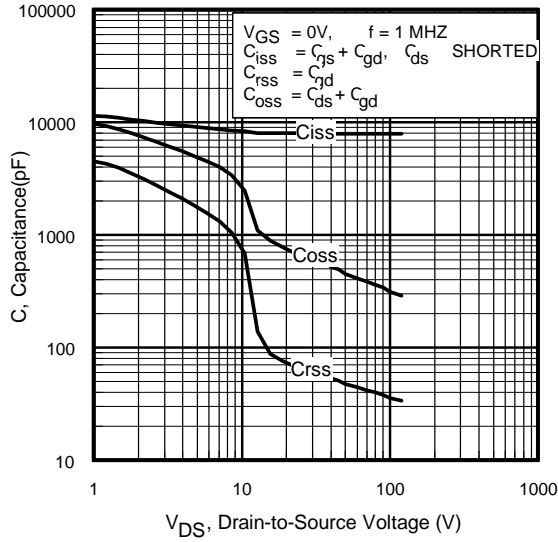
Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.22	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.24	—	
$R_{\theta JA}$	Junction-to-Ambient	—	40	

### Notes:

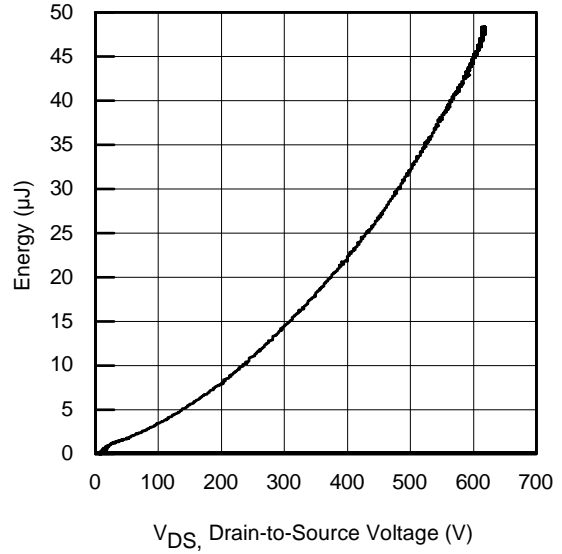
- ① Repetitive rating; pulse width limited by max. junction temperature. (See Fig. 11)
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.91mH$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 38A$ ,  $dv/dt = 13V/ns$ . (See Figure 12a)
- ③  $I_{SD} \leq 38A$ ,  $di/dt \leq 630A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 150^\circ\text{C}$ .
- ④ Pulse width  $\leq 300\mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{oss \text{ eff.}}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .  
 $C_{oss \text{ eff. (ER)}}$  is a fixed capacitance that stores the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .



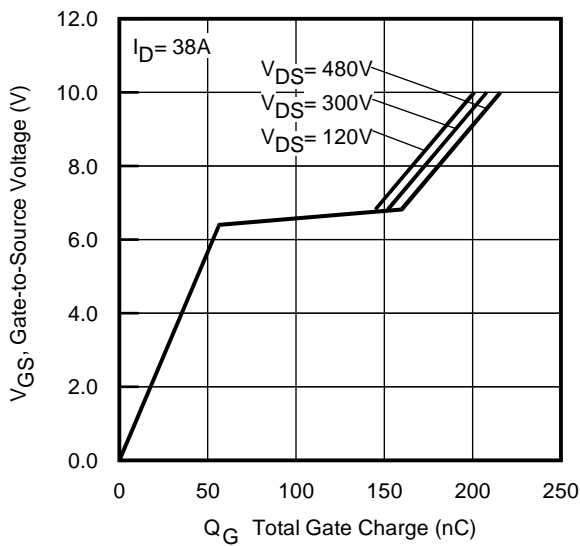
# IRFPS38N60L



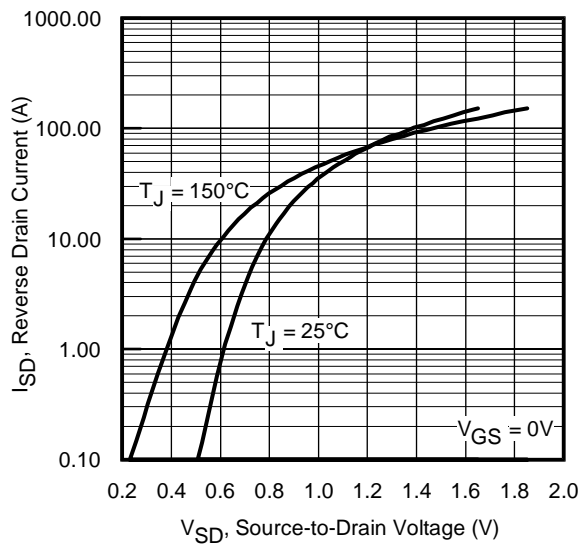
**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



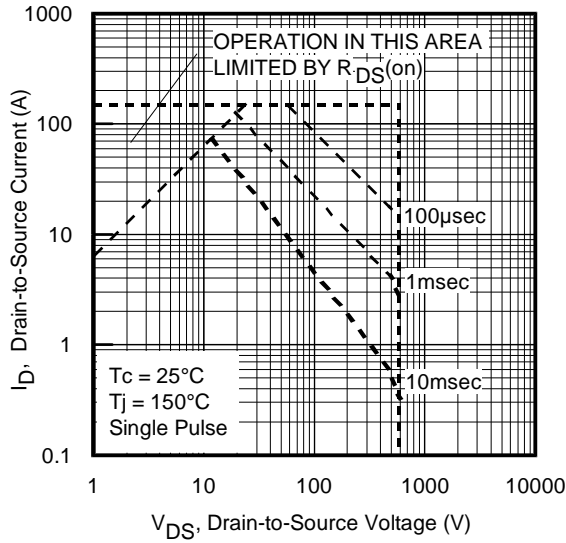
**Fig 6.** Typ. Output Capacitance Stored Energy vs.  $V_{DS}$



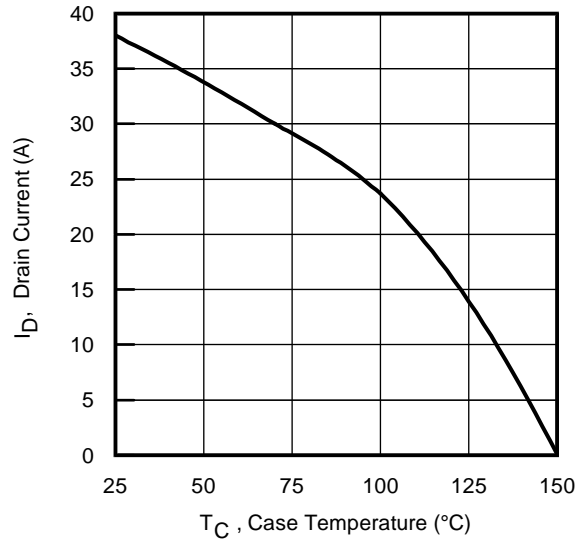
**Fig 7.** Typical Gate Charge vs. Gate-to-Source Voltage



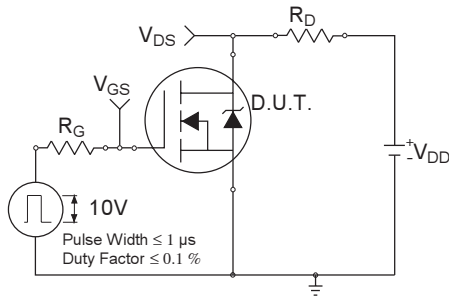
**Fig 8.** Typical Source-Drain Diode Forward Voltage



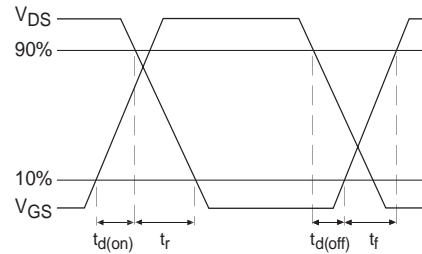
**Fig 9.** Maximum Safe Operating Area



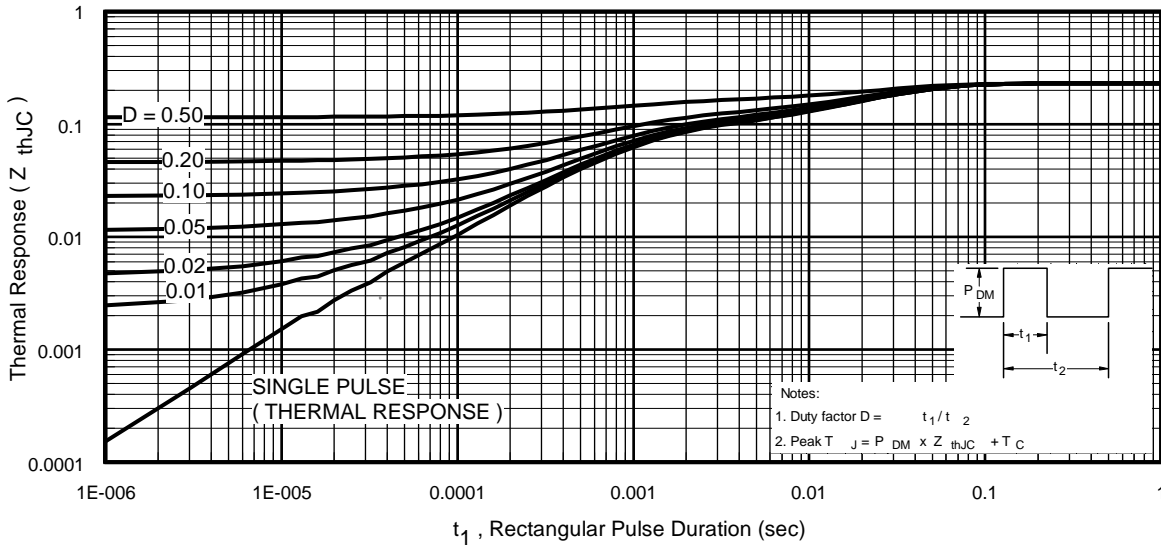
**Fig 10.** Maximum Drain Current vs. Case Temperature



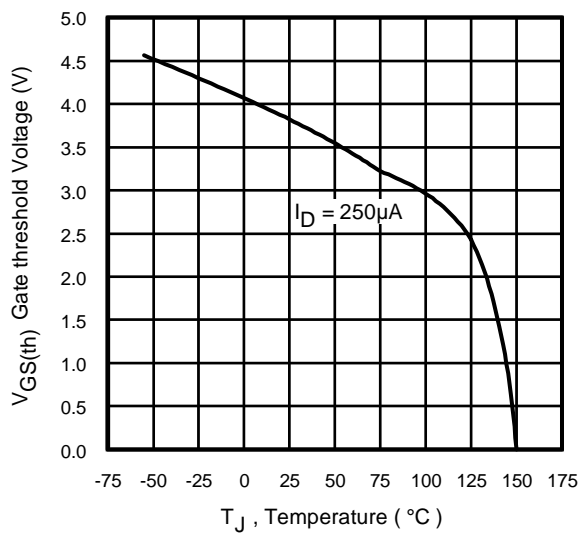
**Fig 11a.** Switching Time Test Circuit



**Fig 11b.** Switching Time Waveforms



**Fig 12.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Fig 13.** Threshold Voltage vs. Temperature

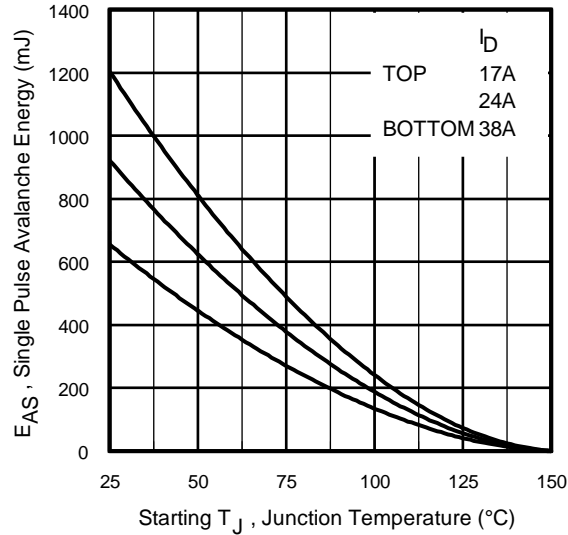


Fig 14a. Maximum Avalanche Energy vs. Drain Current

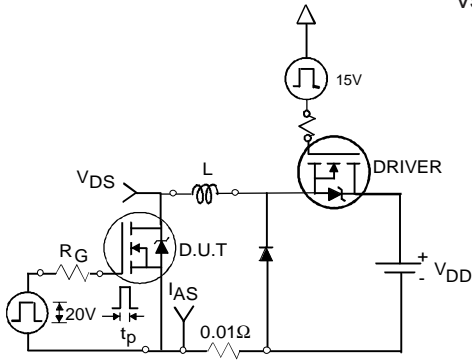


Fig 14b. Unclamped Inductive Test Circuit

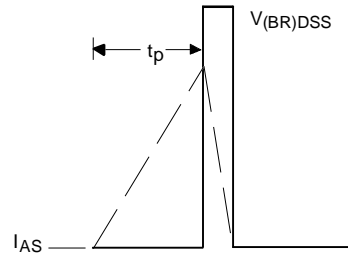


Fig 14c. Unclamped Inductive Waveforms

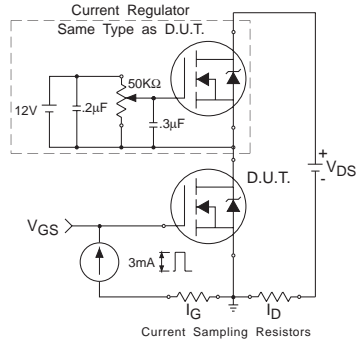


Fig 15a. Gate Charge Test Circuit

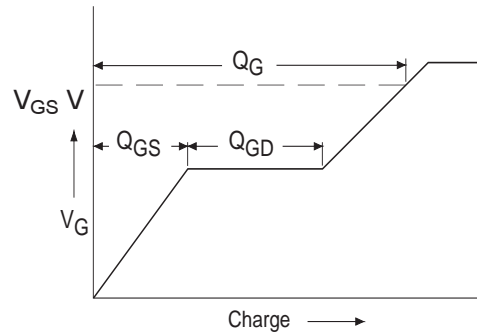
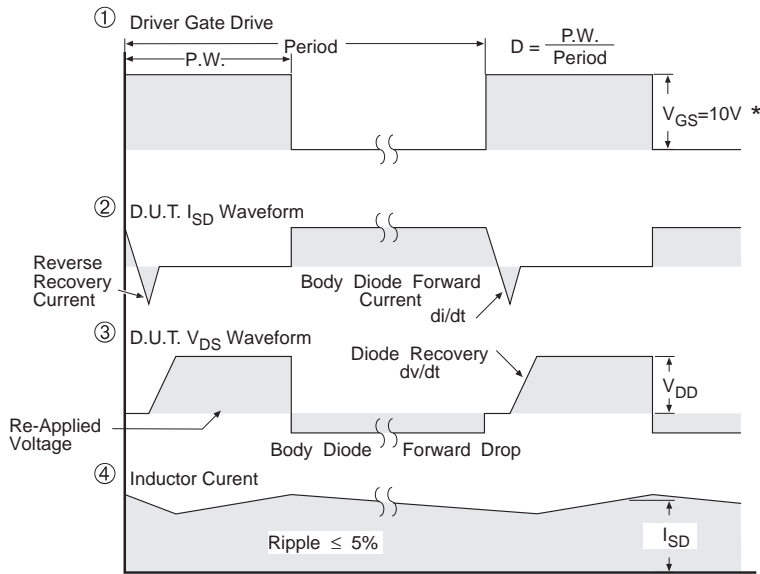
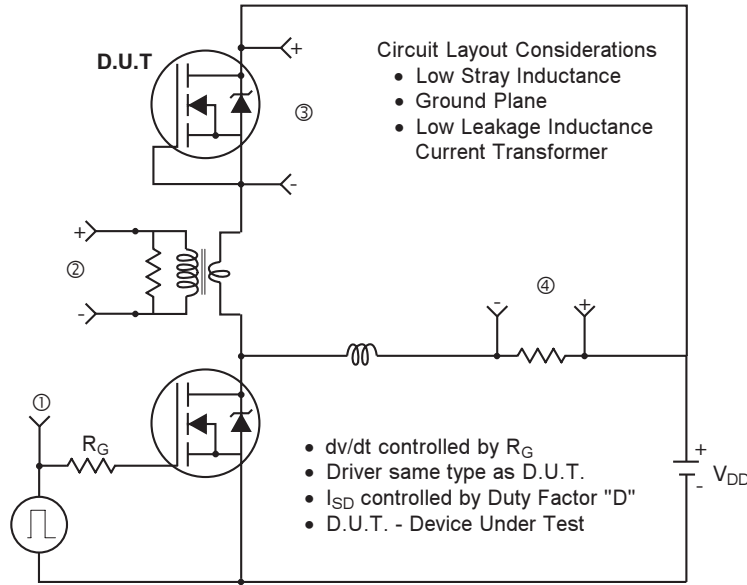


Fig 15b. Basic Gate Charge Waveform

## Peak Diode Recovery dv/dt Test Circuit



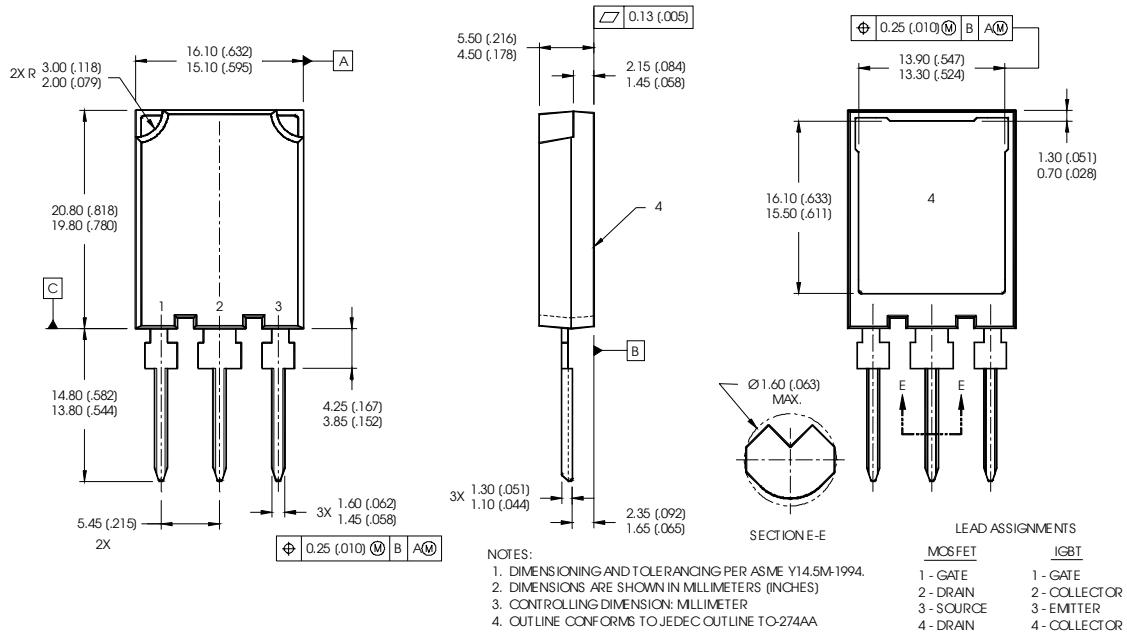
\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 16.** For N-Channel HEXFET<sup>®</sup> Power MOSFETs



## SUPER TO-247AC Package Outline

Dimensions are shown in millimeters (inches)



**Super TO-247AC package is not recommended for Surface Mount Application.**

Data and specifications subject to change without notice.  
 This product has been designed and qualified for the Industrial market.  
 Qualification Standards can be found on IR's Web site.